- Applications Include:

 Buffer/Storage Registers
 Shift Registers

 Pattern Generators
- Flow-Through Architecture to Optimize PCB Layout
- Multiple Center-Pin V_{CC} and GND Configurations to Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

(TOP VIEW)							
1Q[1	U 2	4	CLR			
2Q[2	2	3] 1D			
3Q[3	2	2	2D			
4Q[4	2	1	3D			
GND[5	20	οľ	4D			
GND[6	19	9	V _{CC}			
GND[7	18	В] V _{CC}			
GND[8	1	7	5D			
5Q[9	10	6	6D			
6Q[10	1:	5	7D			
7Q[11	1	4	8D			
8Q[12	: 1:	3] CLK			

DW OR NT PACKAGE

description

These positive-edge-triggered flip-flops implement D-type flip-flop logic with a direct clear input.

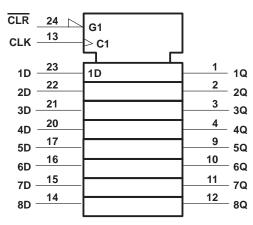
Data at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output.

The 74AC11273 is characterized for operation from – 40°C to 85°C.

FUNCTION TABLE

l	NPUTS		OUTPUT
CLR	CLK	D	Q
L	Х	Χ	L
н	\uparrow	Н	Н
н	\uparrow	L	L
Н	L	Χ	Q_0

logic symbol†

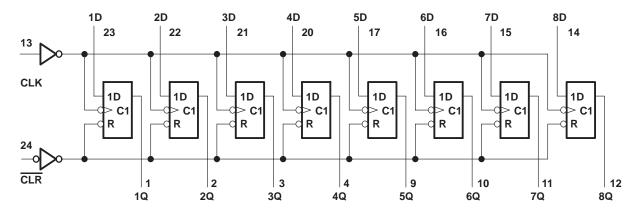


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	\dots -0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	$\dots \dots \pm 50 \text{ mA}$
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	$\dots \dots \pm 50 \text{ mA}$
Continuous current through V _{CC} or GND	$\dots \dots \pm 200 \text{ mA}$
Storage temperature range	– 65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		3	5	5.5	V
		V _{CC} = 3 V	2.1			
VIH	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			V
		V _{CC} = 5.5 V	3.85			
		V _{CC} = 3 V			0.9	
VIL	V _{CC} = 5.5 V	V _{CC} = 4.5 V			1.35	V
		V _{CC} = 5.5 V			1.65	
VI	Input voltage		0		VCC	V
VO	Output voltage		0		VCC	V
		V _{CC} = 3 V			- 4	
lOH	High-level output current	V _{CC} = 4.5 V			- 24	mA
		V _{CC} = 5.5 V			-24	
		V _{CC} = 3 V			12	
IOL	Low-level output current	$V_{CC} = 4.5 V$			24	mA
		$V_{CC} = 5.5 \text{ V}$			24	
Δt/Δν	Input transition rise or fall rate		0		10	ns/V
TA	Operating free-air temperature		- 40		85	°C



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vaa	T,	T _A = 25°C		MINI	MAV	HAIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	IVIIIN	WAX	UNIT
		3 V	2.9			2.9		
	I _{OH} = - 50 μA	4.5 V	4.4			4.4		
		None None						
VOH	I _{OH} = -4 mA	3 V	2.58			2.48		.,
	I _{OH} = -24 mA	4.5 V	3.94			3.8		V
	10H = - 24 IIIA	5.5 V	4.94			4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V						
	I _{OH} = -75 mA [†]	5.5 V				3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
.,	I _{OL} = 12 mA	3 V			0.36		0.44	.,
VOL	lo 24 mA	4.5 V			0.36		0.44	V
	I _{OL} = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V						
	I _{OL} = 75 mA [†]	5.5 V					1.65	
lį	V _I = V _{CC} or GND	5.5 V			± 0.1		± 1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
Ci	V _I = V _{CC} or GND	5 V		4				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			T _A = 2	25°C	MIN	MAX	UNIT	
			MIN	MAX	IVIIIV	IVIAA	UNIT	
fclock	Clock frequency		0	55	0	55	MHz	
t _W Pulse duration	Pulso duration	CLR low	6		6		ns	
	Pulse duration	CLK high or low	9.1		9.1			
		Data	7.5		7.5			
t _{su} Setup time before CLK↑	Setup time before CLK	CLR inactive	6		6		ns	
th	Hold time, data after CLK↑		0		0		ns	

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T _A = 2	25°C	MIN	MAX	UNIT
			MIN	MAX	IVIIIV	IVIAA	UNIT
fclock	Clock frequency		0	80	0	80	MHz
t Dulas duration	CLR low	5		5		20	
'W	t _W Pulse duration	CLK high or low	6.3		6.3		ns
		Data	5		5		
t _{su} Setup time before CLK↑	CLR inactive	4.5		4.5		ns	
th	Hold time, data after CLK↑		0		0		ns



switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO T _A = 25°C		Γ _A = 25°C	MIN	IIN MAX	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN MAX	WAX	ONII
f _{max}			55			55		MHz
t _{PHL}	CLR	Any Q	5.2	14.3	16.5	5.2	18.4	ns
t _{PLH}	CLK	Any	4.2	12.1	14.3	4.2	16.5	ne
^t PHL	CLK	Any Q	5.5	14.5	16.7	5.5	18.6	ns

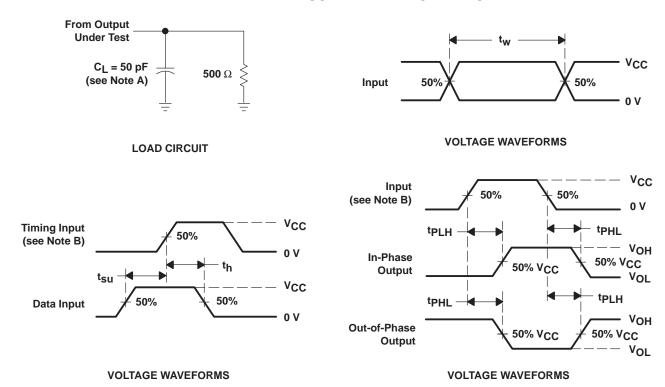
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C			MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIN	IVIAA	UNIT
f _{max}			80			80		MHz
tPHL	CLR	Any Q	4.3	9.2	10.9	4.3	12.3	ns
t _{PLH}	CLK	Any	3.5	7.7	9.3	3.5	10.7	20
t _{PHL}	OLK	Any Q	4.5	9.3	11	4.5	12.4	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	80	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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